

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

Post-silicon validation of IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; **Jutman, Artur**; Squillero, Giovanni; **Tšertov, Anton** 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791546>

Simulation-based equivalence checking between IEEE 1687 ICL and RTL

Damljanovic, Aleksa; **Jutman, Artur**; Portolan, Michele; Tšertov, Anton 2019 IEEE International Test Conference (ITC) 2019 / paper. 7.3, 8 p. : ill <https://doi.org/10.1109/ITC44170.2019.9000181>